



# SSP2N60B/SSS2N60B

## 600V N-Channel MOSFET

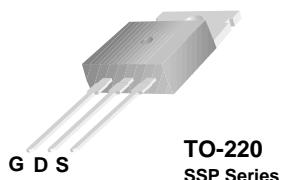
### General Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar, DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switch mode power supplies.

### Features

- 2.0A, 600V,  $R_{DS(on)} = 5.0\Omega @ V_{GS} = 10\text{ V}$
- Low gate charge ( typical 12.5 nC)
- Low  $C_{rss}$  ( typical 7.6 pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability

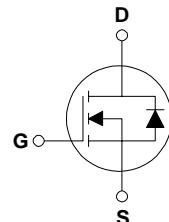
Typical Characteristics



TO-220  
SSP Series



TO-220F  
SSS Series



### Absolute Maximum Ratings

$T_C = 25^\circ\text{C}$  unless otherwise noted

Symbol	Parameter	SSP2N60B	SSS2N60B	Units	
$V_{DSS}$	Drain-Source Voltage	600		V	
$I_D$	Drain Current - Continuous ( $T_C = 25^\circ\text{C}$ )	2.0	2.0 *	A	
	- Continuous ( $T_C = 100^\circ\text{C}$ )	1.3	1.3 *	A	
$I_{DM}$	Drain Current - Pulsed	(Note 1)	6.0	6.0 *	A
$V_{GSS}$	Gate-Source Voltage		$\pm 30$	V	
$E_{AS}$	Single Pulsed Avalanche Energy	(Note 2)	120	mJ	
$I_{AR}$	Avalanche Current	(Note 1)	2.0	A	
$E_{AR}$	Repetitive Avalanche Energy	(Note 1)	5.4	mJ	
$dv/dt$	Peak Diode Recovery $dv/dt$	(Note 3)	5.5	V/ns	
$P_D$	Power Dissipation ( $T_C = 25^\circ\text{C}$ )	54	23	W	
	- Derate above $25^\circ\text{C}$	0.43	0.18	W/ $^\circ\text{C}$	
$T_J, T_{STG}$	Operating and Storage Temperature Range		-55 to +150	$^\circ\text{C}$	
$T_L$	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	$^\circ\text{C}$	

\* Drain current limited by maximum junction temperature.

### Thermal Characteristics

Symbol	Parameter	SSP2N60B	SSS2N60B	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case Max.	2.32	5.5	$^\circ\text{C}/\text{W}$
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink Typ.	0.5	--	$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient Max.	62.5	62.5	$^\circ\text{C}/\text{W}$

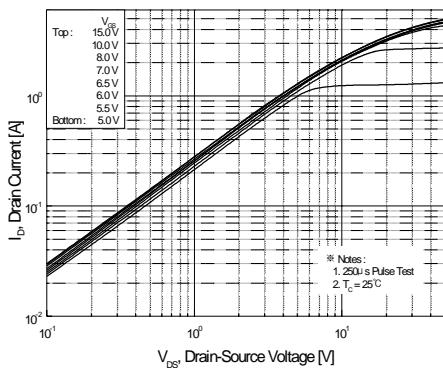
**Electrical Characteristics** $T_C = 25^\circ\text{C}$  unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
<b>Off Characteristics</b>						
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	600	--	--	V
$\Delta BV_{DSS} / \Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu\text{A}$ , Referenced to $25^\circ\text{C}$	--	0.65	--	$\text{V}/^\circ\text{C}$
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 600 \text{ V}, V_{GS} = 0 \text{ V}$	--	--	10	$\mu\text{A}$
		$V_{DS} = 480 \text{ V}, T_C = 125^\circ\text{C}$	--	--	100	$\mu\text{A}$
$I_{GSSF}$	Gate-Body Leakage Current, Forward	$V_{GS} = 30 \text{ V}, V_{DS} = 0 \text{ V}$	--	--	100	nA
$I_{GSSR}$	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$	--	--	-100	nA
<b>On Characteristics</b>						
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	2.0	--	4.0	V
$R_{DS(\text{on})}$	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_D = 1.0 \text{ A}$	--	3.8	5.0	$\Omega$
$g_{FS}$	Forward Transconductance	$V_{DS} = 40 \text{ V}, I_D = 1.0 \text{ A}$ (Note 4)	--	2.05	--	S
<b>Dynamic Characteristics</b>						
$C_{iss}$	Input Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}, f = 1.0 \text{ MHz}$	--	380	490	pF
$C_{oss}$	Output Capacitance		--	35	46	pF
$C_{rss}$	Reverse Transfer Capacitance		--	7.6	9.9	pF
<b>Switching Characteristics</b>						
$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 300 \text{ V}, I_D = 2.0 \text{ A}, R_G = 25 \Omega$	--	16	40	ns
$t_r$	Turn-On Rise Time		--	50	110	ns
$t_{d(off)}$	Turn-Off Delay Time		--	40	90	ns
$t_f$	Turn-Off Fall Time		--	40	90	ns
$Q_g$	Total Gate Charge	$V_{DS} = 480 \text{ V}, I_D = 2.0 \text{ A}, V_{GS} = 10 \text{ V}$	--	12.5	17	nC
$Q_{gs}$	Gate-Source Charge		--	2.2	--	nC
$Q_{gd}$	Gate-Drain Charge		--	5.4	--	nC
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
$I_S$	Maximum Continuous Drain-Source Diode Forward Current		--	--	2.0	A
$I_{SM}$	Maximum Pulsed Drain-Source Diode Forward Current		--	--	6.0	A
$V_{SD}$	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 2.0 \text{ A}$	--	--	1.4	V
$t_{rr}$	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_S = 2.0 \text{ A}, dI_F/dt = 100 \text{ A}/\mu\text{s}$	--	250	--	ns
$Q_{rr}$	Reverse Recovery Charge		--	1.31	--	$\mu\text{C}$

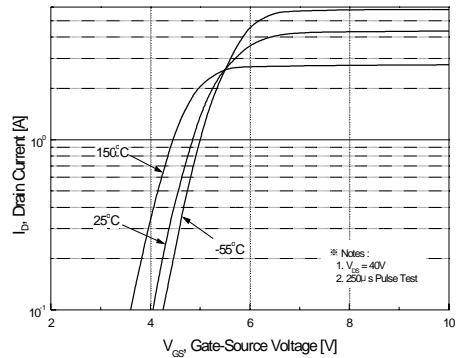
**Notes:**

1. Repetitive Rating : Pulse width limited by maximum junction temperature
2.  $L = 55\text{mH}$ ,  $I_{AS} = 2.0\text{A}$ ,  $V_{DD} = 50\text{V}$ ,  $R_G = 25 \Omega$ , Starting  $T_J = 25^\circ\text{C}$
3.  $I_{SD} \leq 2.0\text{A}$ ,  $dI/dt \leq 300\text{A}/\mu\text{s}$ ,  $V_{DD} \leq BV_{DSS}$ , Starting  $T_J = 25^\circ\text{C}$
4. Pulse Test : Pulse width  $\leq 300\mu\text{s}$ , Duty cycle  $\leq 2\%$
5. Essentially independent of operating temperature

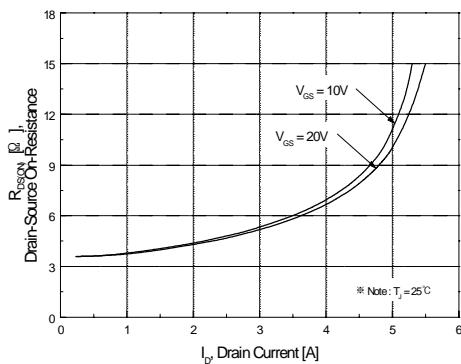
## Typical Characteristics



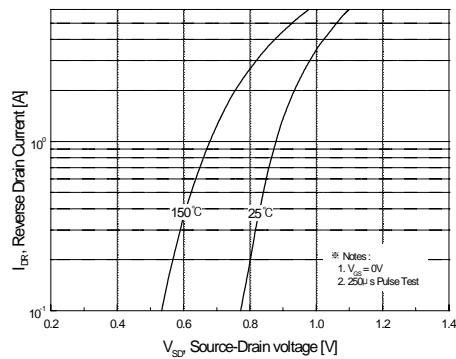
**Figure 1. On-Region Characteristics**



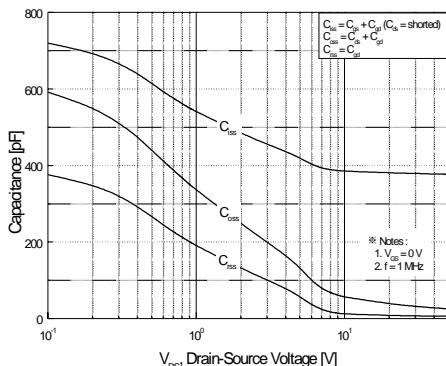
**Figure 2. Transfer Characteristics**



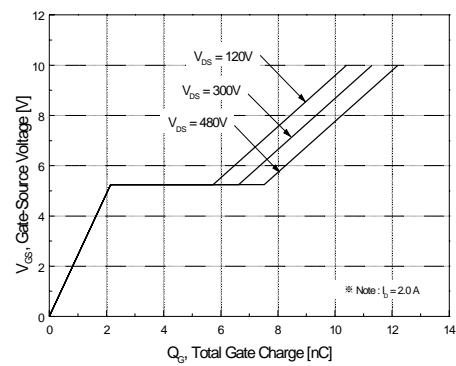
**Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage**



**Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature**

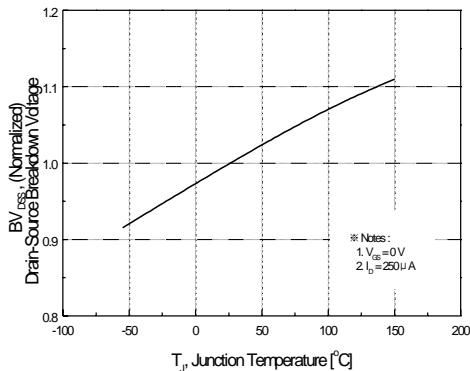


**Figure 5. Capacitance Characteristics**

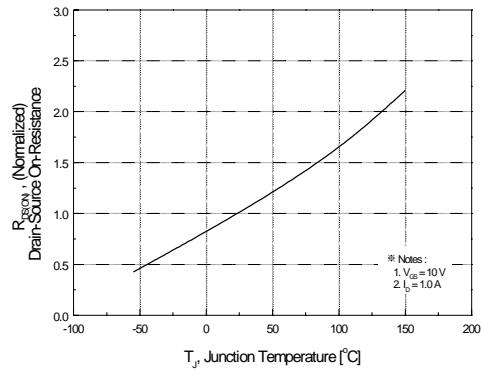


**Figure 6. Gate Charge Characteristics**

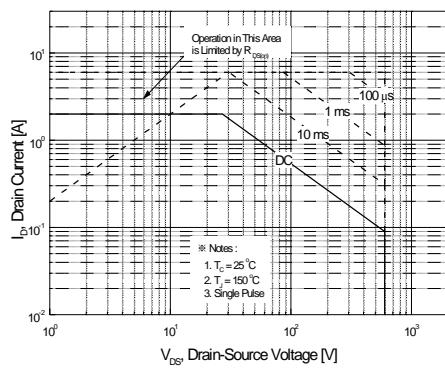
## Typical Characteristics (Continued)



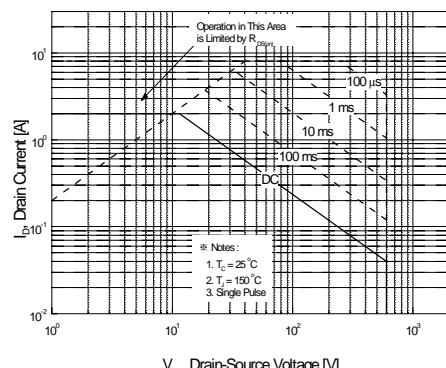
**Figure 7. Breakdown Voltage Variation  
vs Temperature**



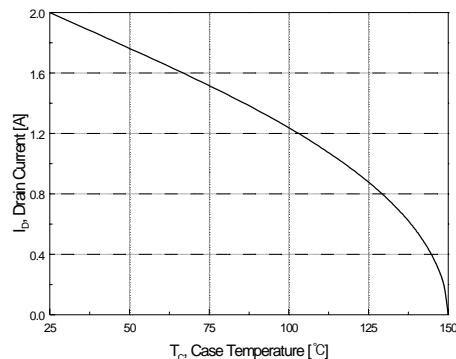
**Figure 8. On-Resistance Variation  
vs Temperature**



**Figure 9-1. Maximum Safe Operating Area  
for SSP2N60B**

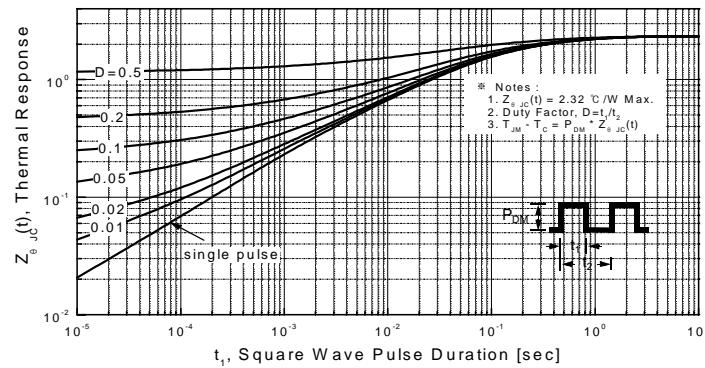


**Figure 9-2. Maximum Safe Operating Area  
for SSS2N60B**

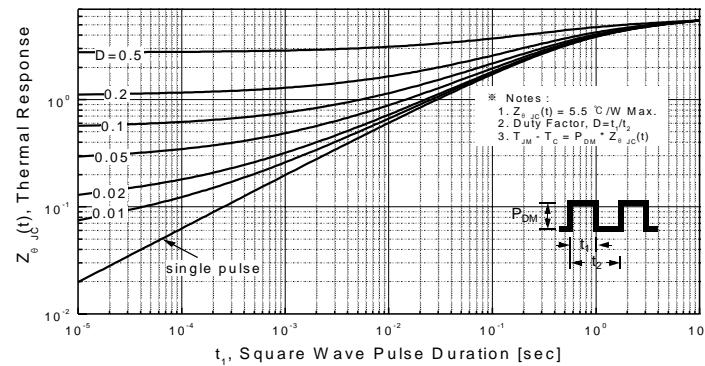


**Figure 10. Maximum Drain Current  
vs Case Temperature**

## Typical Characteristics (Continued)

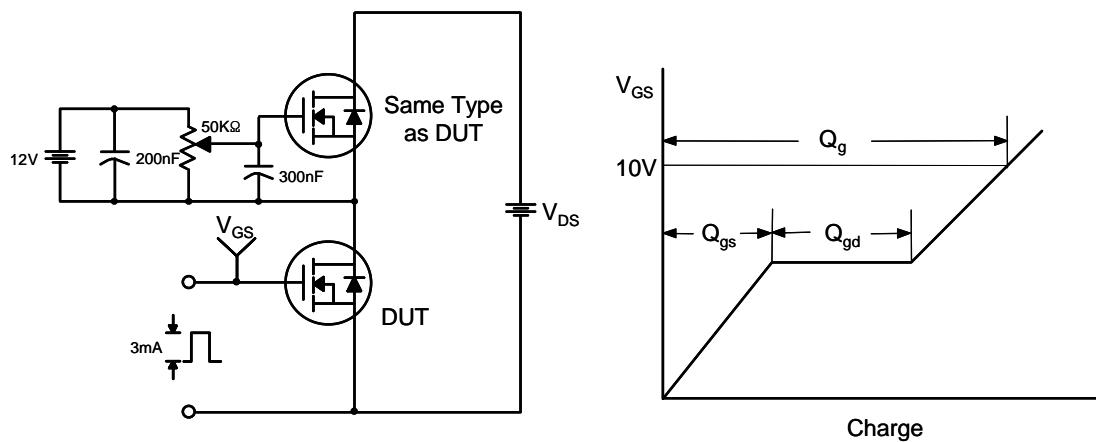


**Figure 11-1. Transient Thermal Response Curve for SSP2N60B**

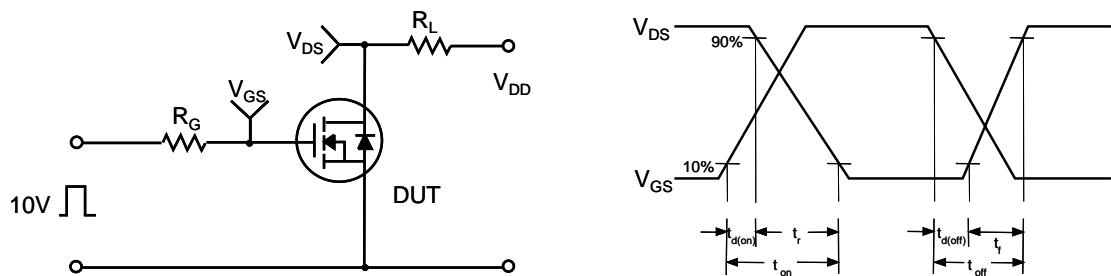


**Figure 11-2. Transient Thermal Response Curve for SSS2N60B**

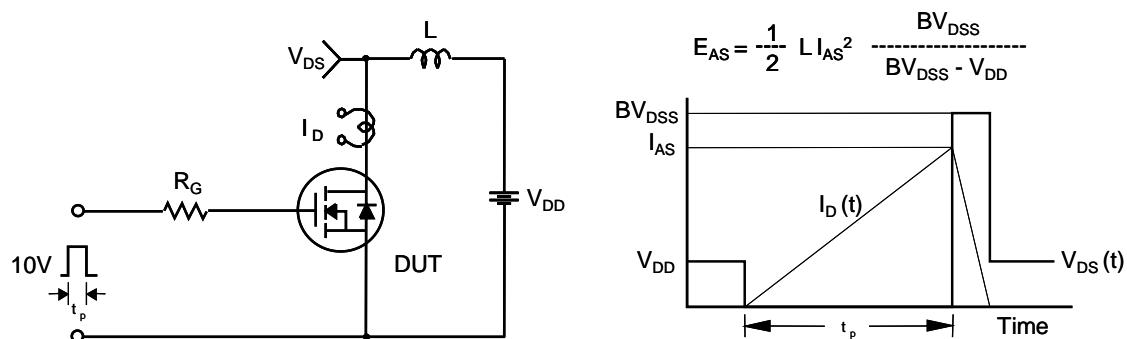
Gate Charge Test Circuit & Waveform



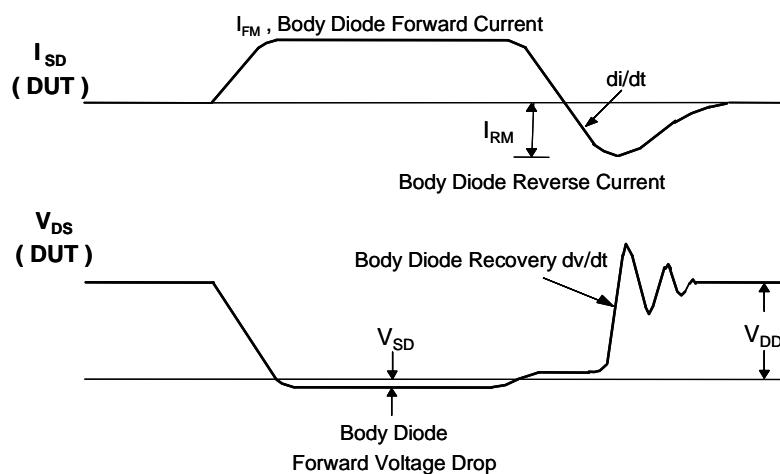
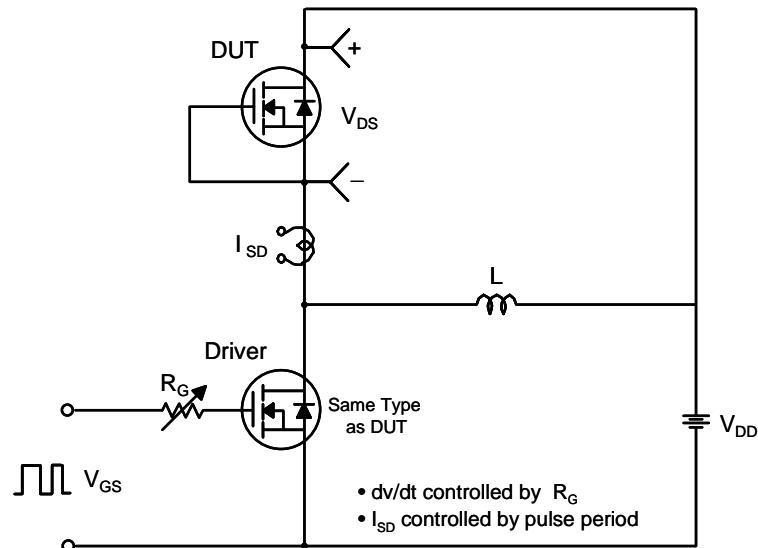
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching Test Circuit & Waveforms

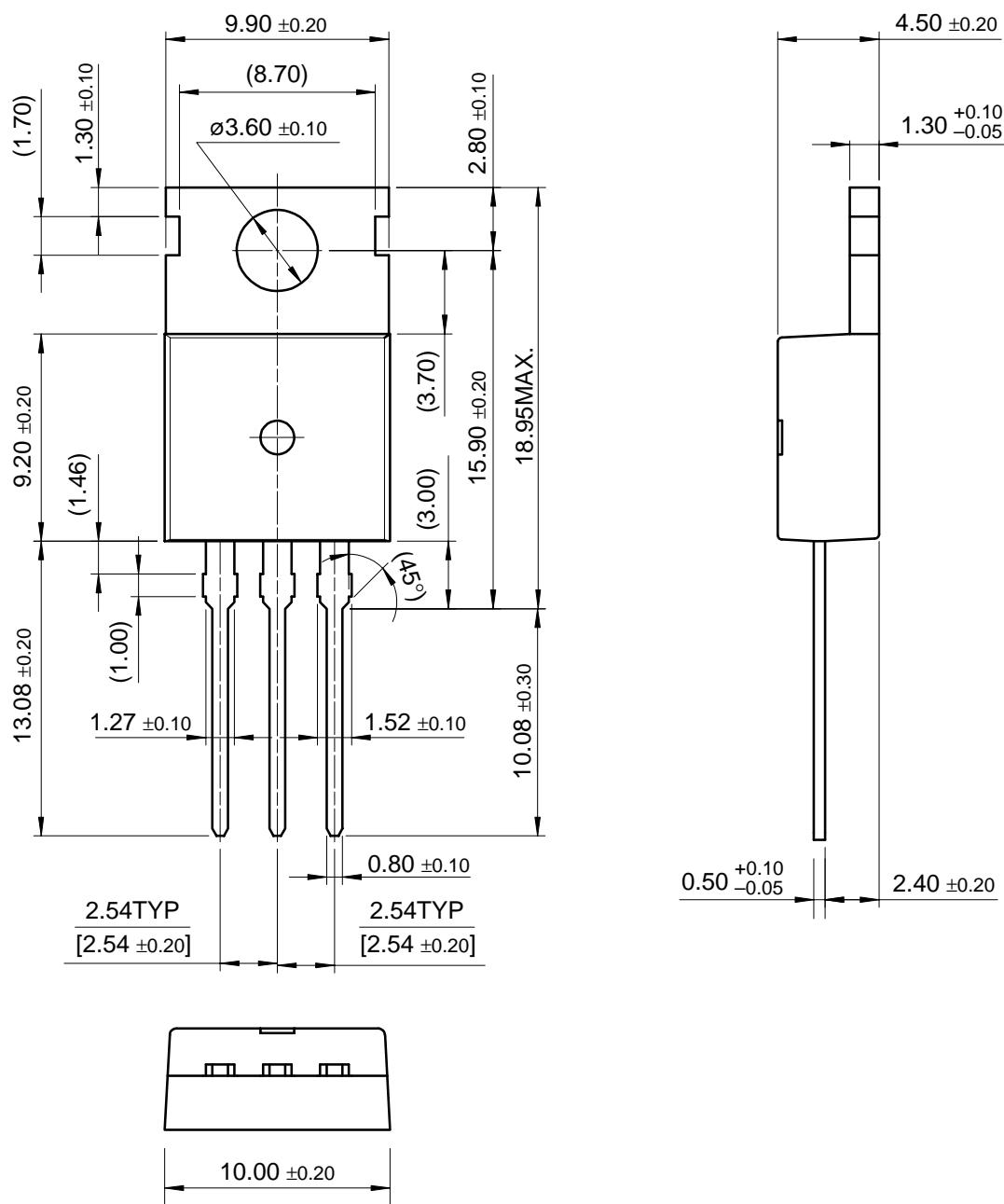


## Peak Diode Recovery dv/dt Test Circuit &amp; Waveforms

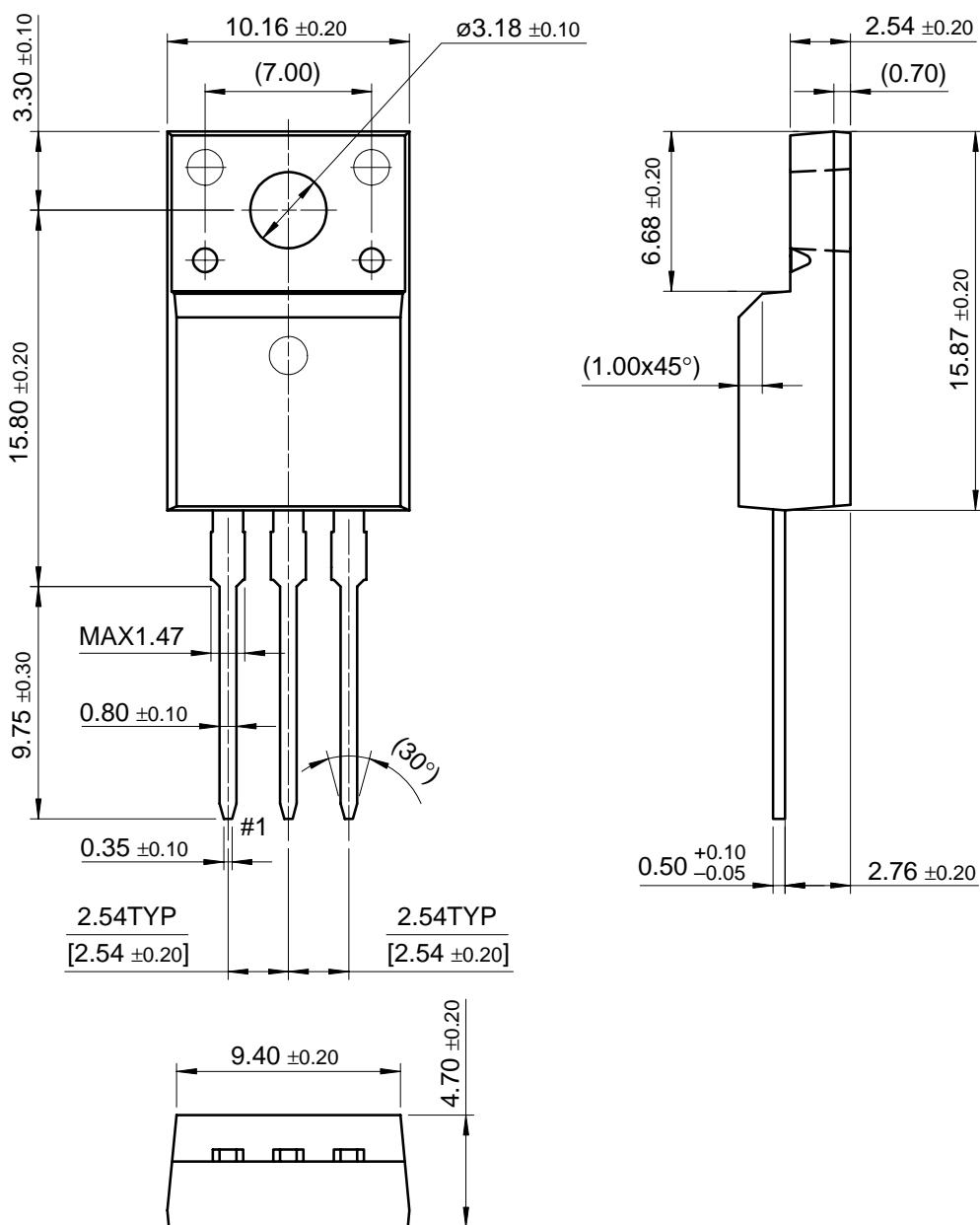


## Package Dimensions

TO-220



Dimensions in Millimeters

**Package Dimensions** (Continued)**TO-220F**

Dimensions in Millimeters

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